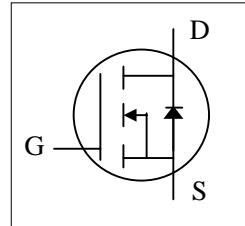


N-CHANNEL ENHANCEMENT MODE POWER MOSFET

PRODUCT SUMMARY

Simple Drive Requirement
Low On-resistance
Fast Switching Characteristic



BV_{DSS}	80V
$R_{DS(ON)}$	13mΩ
I_D	75A

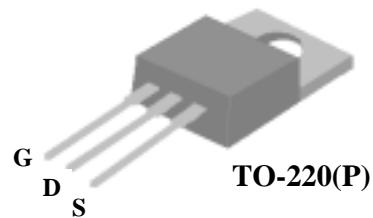
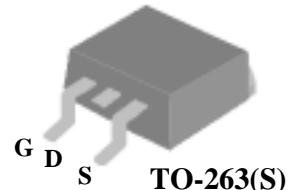
DESCRIPTION

The Advanced Power MOSFETs from Silicon Standard Corp. provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-263 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters. The through-hole version (SSM85T08GP) are available for low-profile applications.



Pb-free; RoHS-compliant



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	80	V
V_{GS}	Gate-Source Voltage	±20	V
$I_D @ T_C=25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	75	A
$I_D @ T_C=100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	48	A
I_{DM}	Pulsed Drain Current ¹	260	A
$P_D @ T_C=25^\circ\text{C}$	Total Power Dissipation	138	W
	Linear Derating Factor	1.11	W/°C
E_{AS}	Single Pulse Avalanche Energy ³	450	mJ
I_{AR}	Avalanche Current	30	A
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

THERMAL DATA

Symbol	Parameter	Value	Units
R_{thj-c}	Thermal Resistance Junction-case	Max.	0.9 °C/W
R_{thj-a}	Thermal Resistance Junction-ambient	Max.	62 °C/W

ELECTRICAL CHARACTERISTICS

@ $T_J=25^{\circ}\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=1\text{mA}$	80	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	-	0.09	-	V/ $^{\circ}\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=45\text{A}$	-	-	13	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=25\text{A}$	-	-	18	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\text{\mu A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_D=45\text{A}$	-	70	-	S
I_{DSS}	Drain-Source Leakage Current ($T_J=25^{\circ}\text{C}$)	$V_{\text{DS}}=80\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	10	\mu A
	Drain-Source Leakage Current ($T_J=150^{\circ}\text{C}$)	$V_{\text{DS}}=64\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	100	\mu A
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}$	-	-	± 100	nA
Q_g	Total Gate Charge ²	$I_D=45\text{A}$	-	63	100	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=64\text{V}$	-	23	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	38	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time ²	$V_{\text{DS}}=40\text{V}$	-	30	-	ns
t_r	Rise Time	$I_D=45\text{A}$	-	100	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_G=10\Omega$, $V_{\text{GS}}=10\text{V}$	-	144	-	ns
t_f	Fall Time	$R_D=0.89\Omega$	-	173	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	6300	10080	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	670	-	pF
C_{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	350	-	pF
R_g	Gate Resistance	f=1.0MHz	-	1.1	1.7	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_S=45\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
t_{rr}	Reverse Recovery Time ²	$I_S=20\text{A}$, $V_{\text{GS}}=0\text{V}$	-	47	-	ns
Q_{rr}	Reverse Recovery Charge	dl/dt=100A/ μs	-	86	-	nC

Notes:

- 1.Pulse width limited by safe operating area.
- 2.Pulse width $\leq 300\text{\mu s}$, duty cycle $\leq 2\%$.
- 3.Starting $T_J=25^{\circ}\text{C}$, $V_{\text{DD}}=30\text{V}$, $L=1\text{mH}$, $R_G=25\Omega$, $I_{\text{AS}}=30\text{A}$.

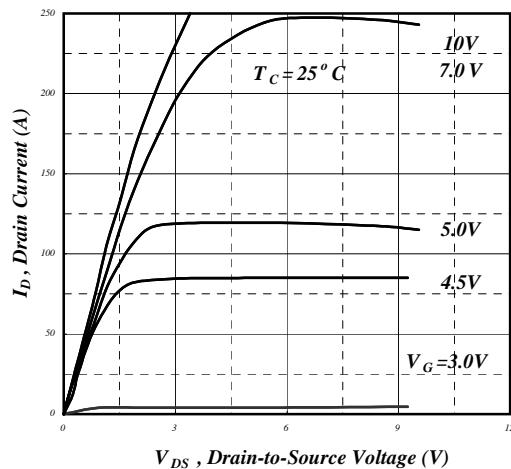


Fig 1. Typical Output Characteristics

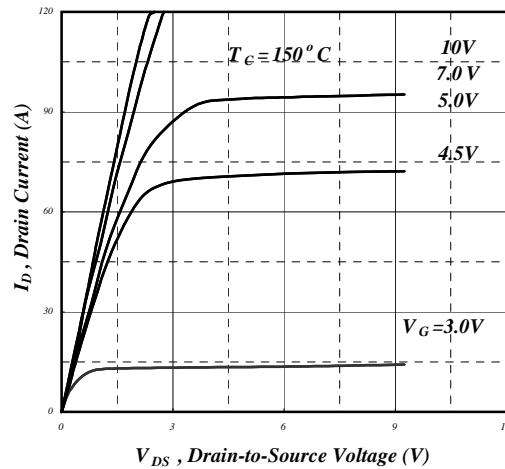


Fig 2. Typical Output Characteristics

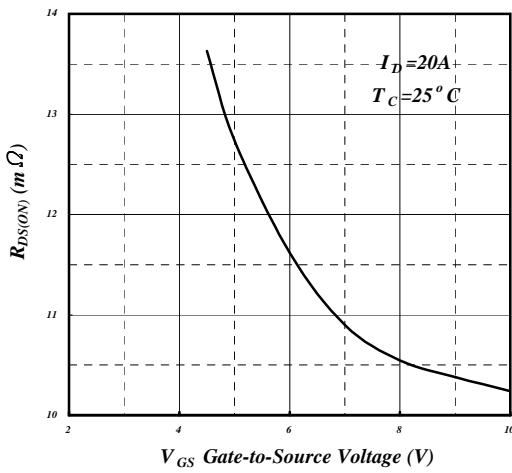


Fig 3. On-Resistance v.s. Gate Voltage

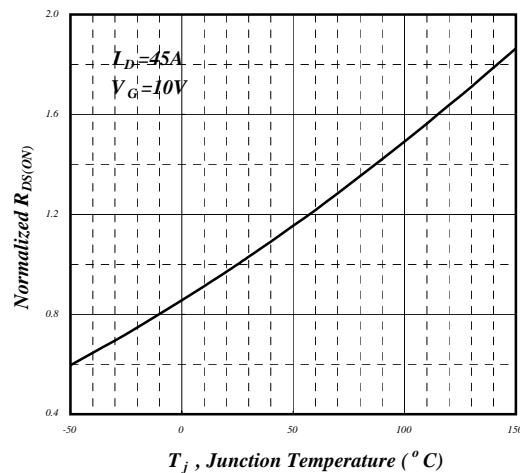


Fig 4. Normalized On-Resistance v.s. Junction Temperature

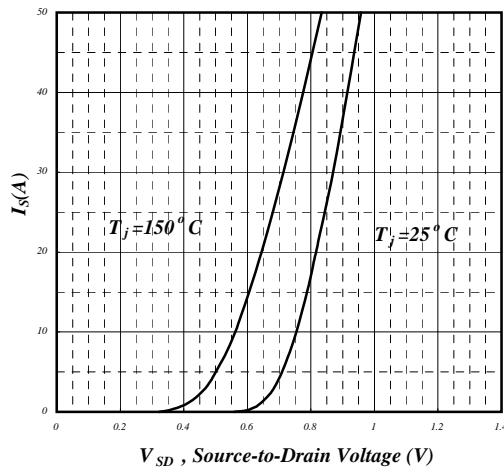


Fig 5. Forward Characteristic of Reverse Diode

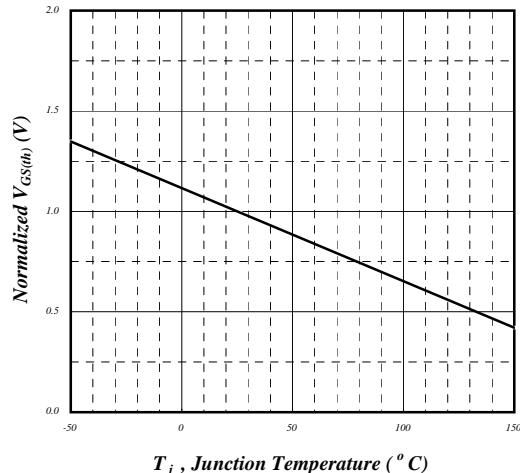


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

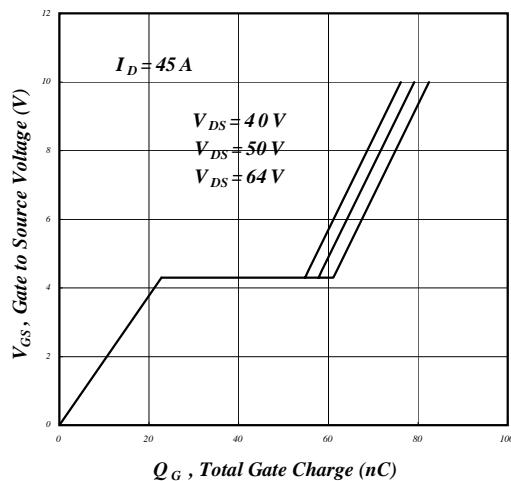


Fig 7. Gate Charge Characteristics

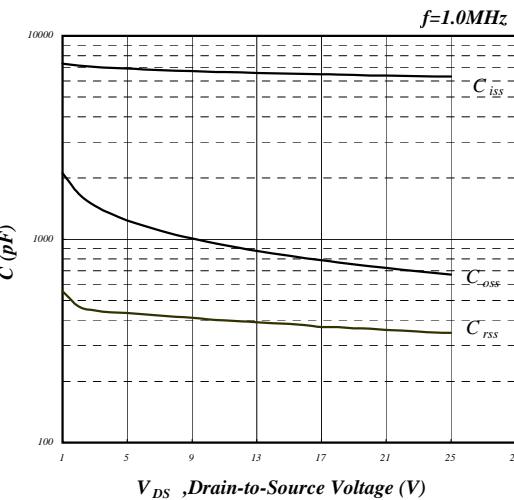


Fig 8. Typical Capacitance Characteristics

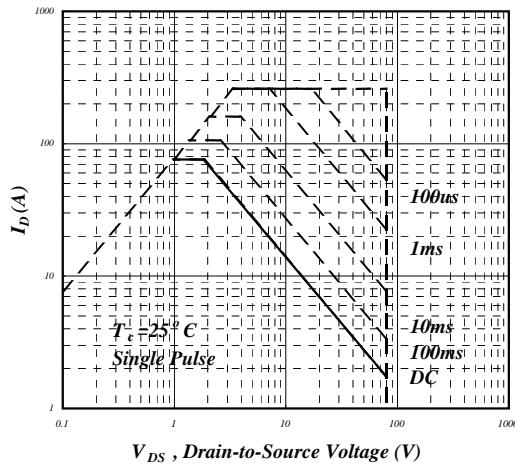


Fig 9. Maximum Safe Operating Area

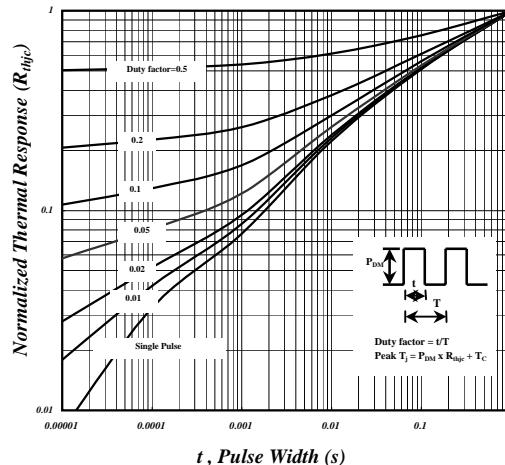


Fig 10. Effective Transient Thermal Impedance

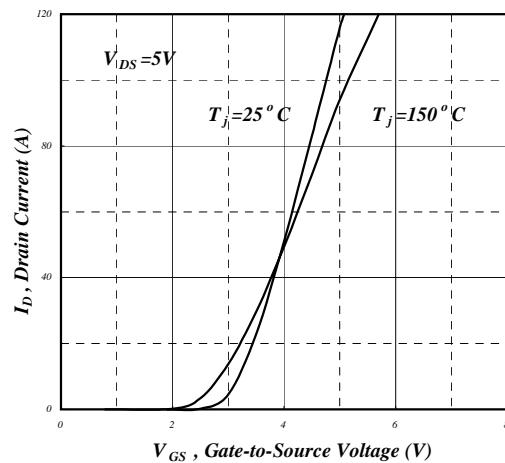


Fig 11. Transfer Characteristics

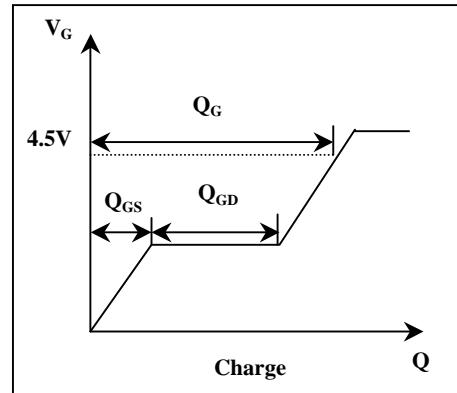


Fig 12. Gate Charge Waveform

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